Data Mining in Cloud-Edge Computing Platforms: Advances and Trends

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Message from the Guest Editors

The aim of the current Research Topic is to cover promising, recent, and novel research trends regarding data mining in edge–cloud platforms. Areas to be covered in this Research Topic may include, but are not limited to:

- New paradigms of data mining in edge–cloud platforms;
- Resource management in edge–cloud platforms;
- Designs to enhance data privacy and security in edge–cloud platforms;
- Designs to mine IoT data in edge–cloud platforms;
- Strategies for decentralized data mining at the edge;
- System and algorithm design for data mining incorporating edge and cloud computing;
- Testbed/benchmarks of data mining for edge–cloud platforms.

Welcome to **contribute**.

Special Issue

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Message from the Editor-in-Chief

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